

**Search Notes**

Application/Control No.

10/727,190

Examiner

Benjamin P. Geib

Applicant(s)/Patent under  
Reexamination

PARK, HEONCHUL

Art Unit

2181

**SEARCHED**

Class	Subclass	Date	Examiner
712	228	3/1/2006	BPG

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Search	3/1/2006	BPG
IEEE Xplore Search	3/1/2006	BPG